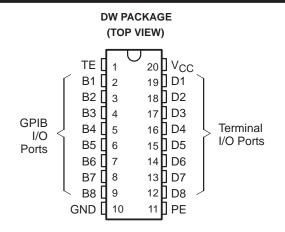
#### **SN75ALS163** OCTAL GENERAL-PURPOSE INTERFACE BUS TRANSCEIVER

SLLS021E - JUNE 1986 - REVISED MAY 1998

- 8-Channel Bidirectional Transceiver
- High-Speed Advanced Low-Power Schottky Circuitry
- Low Power Dissipation . . . 46 mW Max per Channel
- Fast Propagation Times . . . 20 ns Max
- High-Impedance pnp Inputs
- Receiver Hysteresis . . . 650 mV Typ
- **Open-Collector Driver Output Option**
- No Loading of Bus When Device Is Powered Down ( $V_{CC} = 0$ )
- Power-Up/Power-Down Protection (Glitch Free)



#### description

#### NOT RECOMMENDED FOR NEW DESIGNS

The SN75ALS163 octal general-purpose interface bus transceiver is a monolithic, high-speed, advanced low-power Schottky device. It is designed for two-way data communications over single-ended transmission lines. The transceiver features driver outputs that can be operated in either the open-collector or 3-state mode. If talk enable (TE) is high, these outputs have the characteristics of open-collector outputs when pullup enable (PE) is low and of 3-state outputs when PE is high. Taking TE low places the outputs in the high-impedance state. The driver outputs are designed to handle loads of up to 48 mA of sink current. Each receiver features pnp transistor inputs for high input impedance and 400 mV minimum of hysteresis for increased noise immunity.

Output glitches during power up and power down are eliminated by an internal circuit that disables both the bus and receiver outputs. The outputs do not load the bus when  $V_{CC} = 0$ .

The SN75ALS163 is characterized for operation from 0°C to 70°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



#### **Function Tables**

#### **EACH DRIVER**

INPUTS			OUTPUT
D	TE	PE	В
Н	Н	Н	Н
L	Н	Χ	L
Н	X	L	Z
Х	L	Χ	Z

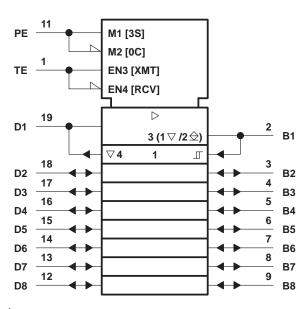
#### **EACH RECEIVER**

INPUTS			OUTPUT
В	TE	D	
L	L	Χ	L
Н	L	X	н
Х	Н	Х	z

H = high level, L = low level,

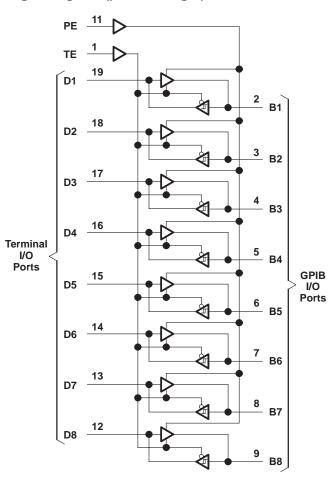
X = irrelevant, Z = high-impedance state

#### logic symbol†



- <sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.
- ∇ Designates 3-state outputs

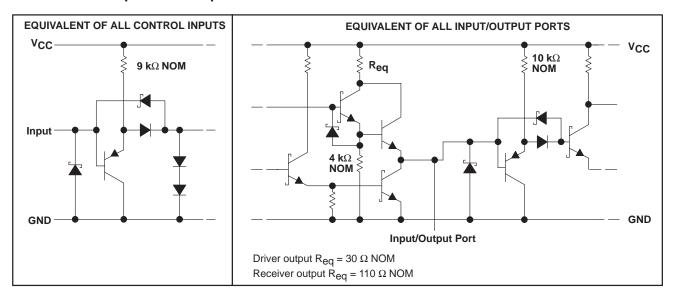
#### logic diagram (positive logic)





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#### schematics of inputs and outputs



#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V <sub>CC</sub> (see Note 1)	
Input voltage, V <sub>I</sub>	5.5 V
Low-level driver output current	100 mA
Package thermal impedance, $\theta_{JA}$ (see Note 2)	97°C/W
Storage temperature range, T <sub>stg</sub>	– 65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from the case for 10 seconds	260°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltage values are with respect to network ground terminal.

#### recommended operating conditions

		MIN	NOM	MAX	UNIT
Supply voltage, V <sub>CC</sub>		4.75	5	5.25	V
High-level input voltage, VIH		2			V
Low-level input voltage, V <sub>IL</sub>				0.8	V
High level output ourrent leve	Bus ports with pullups active			- 5.2	mA
High-level output current, IOH	Terminal ports			- 800	μΑ
1 1 1	Bus ports			48	А
Low-level output current, I <sub>OL</sub>	Terminal ports			16	mA
Operating free-air temperature, T <sub>A</sub>		0		70	°C

<sup>2.</sup> The package thermal impedance is calculated in accordance with JESD 51.

#### SN75ALS163 OCTAL GENERAL-PURPOSE INTERFACE BUS TRANSCEIVER

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## electrical characteristics over recommended supply-voltage and operating free-air temperature ranges (unless otherwise noted)

PARAMETER			TEST CONDITIONS			TYP†	MAX	UNIT	
VIK	Input clamp voltage		I <sub>I</sub> = -18 mA			- 0.8	-1.5	V	
V <sub>hys</sub>	Hysteresis (V <sub>T+</sub> – V <sub>T-</sub> )	Bus			0.4	0.65		V	
V	High-level output voltage	Terminal	al $I_{OH} = -800 \mu\text{A}$ , TE at 0.8 V		2.7	3.5		V	
VOH		Bus	$I_{OH} = -5.2 \text{ mA},$	PE and TE at 2 V	2.5	3.3		'	
\/o.	l llttt	Terminal	I <sub>OL</sub> = 16 mA,	TE at 0.8 V		0.3	0.5	V	
VOL	Low-level output voltage	Bus	I <sub>OL</sub> = 48 mA,	TE at 2 V		0.35	0.5	V	
lOH	High-level output current (open-collector mode)	Bus	V <sub>O</sub> = 5.5 V,	PE at 0.8 V, D and TE at 2 V			100	μΑ	
Off-state output current		PE at 2 V,		V <sub>O</sub> = 2.7 V			20		
loz	(3-state mode)	Dus	TE at 0.8 V	V <sub>O</sub> = 0.5 V			-100	μΑ	
II	Input current at maximum input voltage	Terminal	V <sub>I</sub> = 5.5 V			0.2	100	μΑ	
lн	High-level input current	Terminal,	V <sub>I</sub> = 2.7 V	V <sub>I</sub> = 2.7 V		0.1	20	μΑ	
IIL	Low-level input current	PE, or TE	V <sub>I</sub> = 0.5 V			-10	-100	μΑ	
la a	Short-circuit output current	Terminal			- 15	- 35	<b>–</b> 75	Λ	
los		Bus			- 25	- 50	-125	mA	
Icc	Supply current		No load	Terminal outputs low and enabled		42	65	mA	
	<u> </u>			Bus outputs low and enabled		52	80		
C <sub>I/O(bus)</sub>	I/O(bus) Bus-port capacitance		$V_{CC} = 0 \text{ to } 5 \text{ V},$	$V_{I/O} = 0 \text{ to } 2 \text{ V}, \qquad f = 1 \text{ MHz}$		30		pF	

 $<sup>\</sup>dagger$  All typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C.

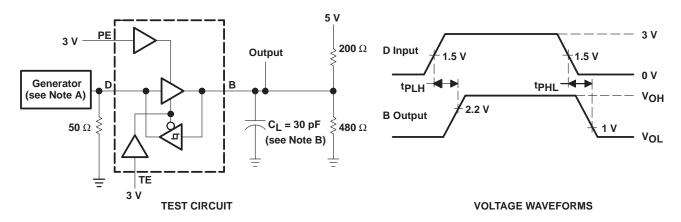
### switching characteristics over recommended operating free-air temperature range (unless otherwise noted), $V_{CC} = 5 \text{ V}$

PARAMETER		FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN TYPT	MAX	UNIT	
tPLH	Propagation delay time, low-to-high-level output	Torminal	Ferminal Bus	C <sub>L</sub> = 30 pF, See Figure 1	7	20	ns	
<sup>t</sup> PHL	Propagation delay time, high-to-low-level output	Terminai			8	20		
<sup>t</sup> PLH	Propagation delay time, low-to-high-level output	Puo	Terminal		C <sub>I</sub> = 30 pF,	7	14	
tPHL	Propagation delay time, high-to-low-level output	Bus		See Figure 2	9	14	ns	
<sup>t</sup> PZH	Output enable time to high level				19	30		
tPHZ	Output disable time from high level	TE	Bus	C <sub>L</sub> = 15 pF,	5	12	ns	
tPZL	Output enable time to low level	] '-	Bus	See Figure 3	16	35	115	
tPLZ	Output disable time from low level				9	20		
tPZH	Output enable time to high level				13	30		
t <sub>PHZ</sub>	Output disable time from high level	TE	Terminal	C <sub>L</sub> = 15 pF,	12	20		
t <sub>PZL</sub>	Output enable time to low level	I E	15	rerminai	See Figure 4	12	20	ns
tPLZ	Output disable time from low level	]			11	20		
t <sub>en</sub>	Output pull-up enable time	PE	Puo	C <sub>L</sub> = 15 pF,	11	22		
t <sub>dis</sub>	Output pull-up disable time	FC	Bus	See Figure 5	6	12	ns	

<sup>†</sup> All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

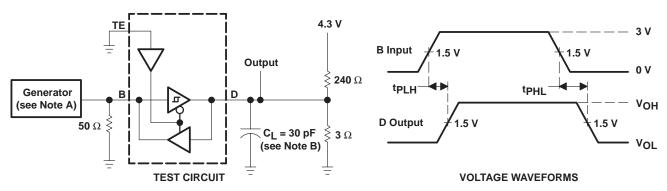


#### PARAMETER MEASUREMENT INFORMATION



- NOTES: A. The input pulse is supplied by a generator having the following characteristics: PRR  $\leq$  1 MHz, 50% duty cycle,  $t_f \leq$  6 ns,  $t_f \leq$  6 ns,  $t_f \leq$  6 ns,  $t_f \leq$  0 ns,  $t_f \leq$  1 MHz, 50% duty cycle,  $t_f \leq$  1 ns,  $t_f \leq$  2 ns,  $t_f \leq$  1 ns,  $t_f \leq$  2 ns,  $t_f \leq$  3 ns,  $t_f \leq$  3 ns,  $t_f \leq$  3 ns,  $t_f \leq$  4 ns,  $t_f \leq$  5 ns,  $t_f \leq$  5 ns,  $t_f \leq$  6 ns,  $t_f \leq$  8 ns,  $t_f \leq$  8 ns,  $t_f \leq$  9 ns, t
  - B. C<sub>L</sub> includes probe and jig capacitance.

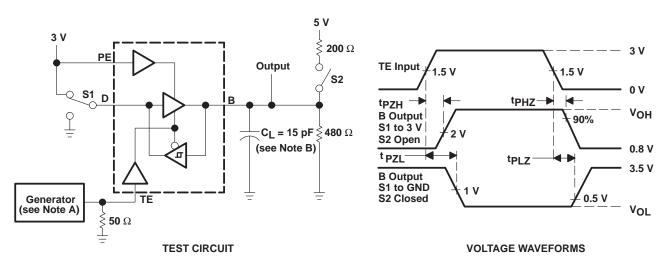
Figure 1. Terminal-to-Bus Test Circuit and Voltage Waveforms



- NOTES: A. The input pulse is supplied by a generator having the following characteristics: PRR  $\leq$  1 MHz, 50% duty cycle,  $t_f \leq$  6 ns,  $t_f \leq$  8 ns,  $t_f \leq$  8 ns,  $t_f \leq$  9 ns,  $t_f$ 
  - B. C<sub>L</sub> includes probe and jig capacitance.

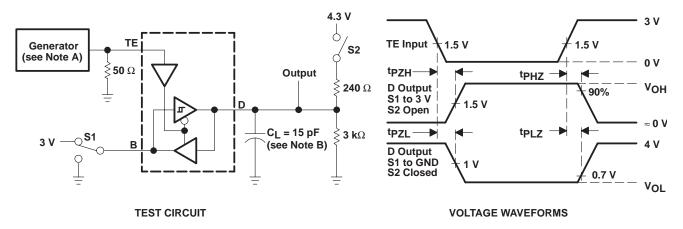
Figure 2. Bus-to-Terminal Test Circuit and Voltage Waveforms

#### PARAMETER MEASUREMENT INFORMATION



- NOTES: A. The input pulse is supplied by a generator having the following characteristics: PRR  $\leq$  1 MHz, 50% duty cycle,  $t_r \leq$  6 ns,  $t_f \leq$  6 ns,  $t_f \leq$  6 ns,  $t_f \leq$  0 ns,  $t_f \leq$  1 MHz, 50% duty cycle,  $t_f \leq$  1 ns,  $t_f \leq$  2 ns,  $t_f \leq$  1 ns,  $t_f \leq$  1 ns,  $t_f \leq$  2 ns,  $t_f \leq$  1 ns,  $t_f \leq$  2 ns,  $t_f \leq$  3 ns,  $t_f \leq$  3 ns,  $t_f \leq$  3 ns,  $t_f \leq$  4 ns,  $t_f \leq$  3 ns,  $t_f \leq$  4 ns,  $t_f \leq$  5 ns,  $t_f \leq$  5 ns,  $t_f \leq$  6 ns,  $t_f \leq$  8 ns,  $t_f \leq$  8 ns,  $t_f \leq$  9 ns, t
  - B. C<sub>L</sub> includes probe and jig capacitance.

Figure 3. TE-to-Bus Test Circuit and Voltage Waveforms



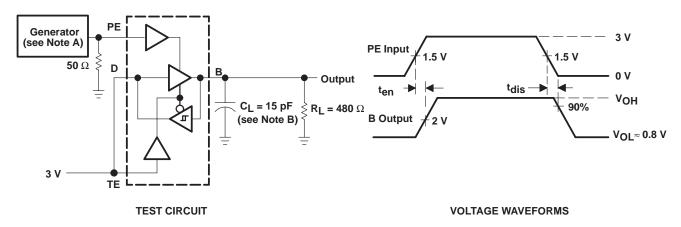
- NOTES: A. The input pulse is supplied by a generator having the following characteristics: PRR  $\leq$  1 MHz, 50% duty cycle,  $t_{\Gamma} \leq$  6 ns,  $t_{\Gamma} \leq$  7 ns,  $t_{\Gamma} \leq$  8 ns,  $t_{\Gamma} \leq$  9 ns,  $t_$ 
  - B. C<sub>L</sub> includes probe and jig capacitance.

Figure 4. TE-to-Terminal Test Circuit and Voltage Waveforms

#### SN75ALS163 OCTAL GENERAL-PURPOSE INTERFACE BUS TRANSCEIVER

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#### PARAMETER MEASUREMENT INFORMATION



NOTES: A. The input pulse is supplied by a generator having the following characteristics: PRR  $\leq$  1 MHz, 50% duty cycle,  $t_f \leq$  6 ns,  $t_f \leq$  7 ns,  $t_f \leq$  8 ns,  $t_f \leq$  8 ns,  $t_f \leq$  8 ns,  $t_f \leq$  9 ns,  $t_f$ 

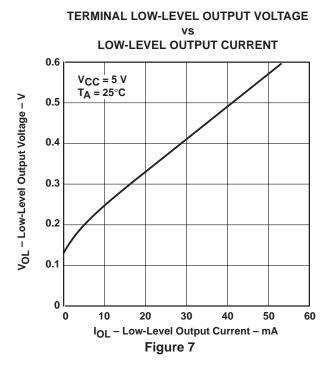
B. C<sub>L</sub> includes probe and jig capacitance.

Figure 5. PE-to-Bus Test Circuit and Voltage Waveforms

#### **TYPICAL CHARACTERISTICS**

## TERMINAL HIGH-LEVEL OUTPUT VOLTAGE vs HIGH-LEVEL OUTPUT CURRENT VCC = 5 V TA = 25°C TA = 25°C 1.5 0 0 -5 -10 -15 10H High-Level Output Current - mA

Figure 6



#### **TERMINAL OUTPUT VOLTAGE**

## BUS INPUT VOLTAGE

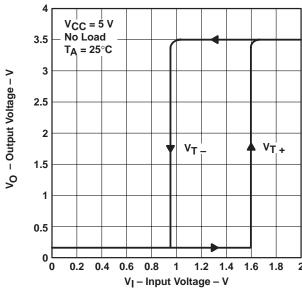


Figure 8

#### TYPICAL CHARACTERISTICS

# BUS HIGH-LEVEL OUTPUT CURRENT VCC = 5 V TA = 25°C O -10 -20 -30 -40 -50 -60 IOH - High-Level Output Current - mA

Figure 9

BUS LOW-LEVEL OUTPUT VOLTAGE vs
BUS LOW-LEVEL OUTPUT CURRENT

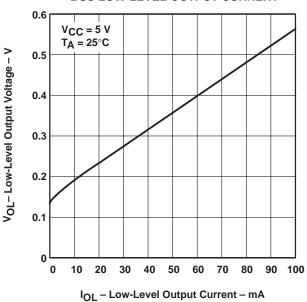


Figure 10

## BUS OUTPUT VOLTAGE vs TERMINAL INPUT VOLTAGE

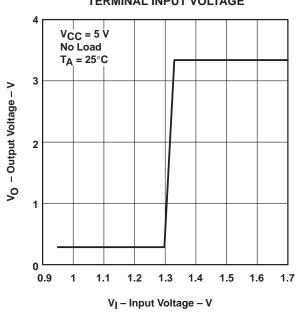


Figure 11

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